Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-189001 Application No. 10/735,767 Applicant Hideaki Kuwabara et al.		
	closure Statement			
(Use several sh	eets if necessary)	Filing Date December 16, 2003	Group Art Unit 2822	
(37 CFR §1.98(b))				

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Examiner Initial	Desig.	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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KP	AP	European Search Report dated August 22, 2006 for European Patent Office Application No.: 03029012.6, 5 pages				
KP	AQ	Zhang, X. et al., "Thermal Conductivity and Diffusivity of Free-Standing Silicon Nitride Thin Films"; Review of Scientific Instruments, Vol. 66, No. 2, Part 1; pp. 1115-1120; 02/1995				
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U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 12732-189001

Application No. 10/735,767

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Applicant Hideaki Kuwabara et al.

Filing Date

December 16, 2003

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